4/16/2014

RELIABILITY MONITOR REPORT
FOR

MFN 80V Bipolar CMOS DMOS (BCD88)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX6769TALD

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 15503 QUANTITY: 80 FAILS: 0 FITS: 7.4

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2013 and 3/31/2014 .

Process Information:

Process Description: MFN 80V Bipolar CMOS DMOS (BCD88)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1121	MAX6769TALD2+	135°C	1000 HRS	80	0	J984DQ001A#
				Total:		**0**	

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